## MOTOROLA SEMICONDUCTOR TECHNICAL DATA

### Advance Information

# TMOS E-FET ™ Power Field Effect Transistor N-Channel Enhancement-Mode Silicon Gate

This advanced TMOS E-FET is designed to withstand high energy in the avalanche and commutation modes. The new energy efficient design also offers a drain-to-source diode with a fast recovery time. Designed for high voltage, high speed switching applications in power supplies, converters and PWM motor controls, these devices are particularly well suited for bridge circuits where diode speed and commutating safe operating areas are critical and offer additional safety margin against unexpected voltage transients.

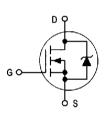
- Avalanche Energy Specified
- Source-to-Drain Diode Recovery Time Comparable to a Discrete Fast Recovery Diode
- · Diode is Characterized for Use in Bridge Circuits
- IDSS and VDS(on) Specified at Elevated Temeprature

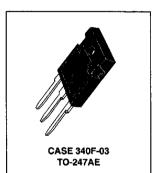




Motorola Preferred Device

TMOS POWER FET 6.0 AMPERES RDS(on) = 1.20 OHM 600 VOLTS





#### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Rating	Symbol	Value	Ųnit
Drain-Source Voltage	VDSS	600	Vdc
Drain-Gate Voltage (R <sub>GS</sub> = 1 0 MΩ)	VDGR	600	Vdc
Gate-Source Voltage — Continuous	V <sub>GS</sub>	±20	Vdc
Drain Current — Continuous @ $T_C = 25^{\circ}C$ — Continuous @ $T_C = 100^{\circ}C$ — Single Pulse ( $t_p \le 10 \mu s$ )	I <sub>D</sub>	6 0 5 0 25	Adc Apk
Total Power Dissipation @ T <sub>C</sub> = 25°C Derate above 25°C	PD	150 1 0	Watts W/°C
Operating and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	-55 to 150	°C
Single Pulse Drain-to-Source Avalanche Energy — Starting T <sub>J</sub> = 25°C (V <sub>DD</sub> = 50 Vdc, V <sub>GS</sub> = 10 Vpk, I <sub>L</sub> = 6 0 Apk, L = 10 4 mH, R <sub>G</sub> = 25 Ω)	EAS	187	mJ
Thermal Resistance — Junction to Case — Junction to Ambient	R <sub>OJC</sub> R <sub>OJA</sub>	1.0 40	°C/W
Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 5 seconds	ΤL	260	°C

This document contains information on a new product. Specifications and information are subject to change without notice

E-FET is a trademark of Motorola Inc.

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Preferred devices are Motorola recommended choices for future use and best overall value

### ELECTRICAL CHARACTERISTICS (To = 25°C unless otherwise noted)

Cha	racteristic	Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage (VGS = 0 V, I <sub>D</sub> = 250 μAdc) Temperature Coefficient (Positive	3)	BV <sub>DSS</sub>	600	 360	_	Vdc mV/°C
Zero Gate Voltage Drain Current $(V_{DS} = 600 \text{ Vdc}, V_{GS} = 0)$ $(V_{DS} = 600 \text{ Vdc}, V_{GS} = 0, T_J =$	125°C)	IDSS	_	_	250 1000	μAdc
Gate-Body Leakage Current (VGS = ±20 Vdc, VDS = 0)		IGSS	_		100	nAdc
ON CHARACTERISTICS*						
Gate Threshold Voltage (V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 μAdc) Temperature Coefficient (Negativ	re)	VGS(th)	2.0 —	 5.0	4 0 —	Vdc mV/°C
Static Drain-Source On-Resistance (VGS = 10 Vdc, ID = 5.0 Adc)		R <sub>DS(on)</sub>	_		1.2	Ohm
Drain-Source On-Voltage (V <sub>GS</sub> = 1 (I <sub>D</sub> = 6.0 Adc) (I <sub>D</sub> = 3.0 Adc, T <sub>J</sub> = 125°C)	0 Vdc)	V <sub>DS(on)</sub>	<u> </u>		8.0 7.2	Vpk
Forward Transconductance (VDS :	= 15 Vdc, I <sub>D</sub> = 3.0 Adc)	9FS	2.5	_		mhos
DYNAMIC CHARACTERISTICS						
Input Capacitance	(V <sub>DS</sub> = 25, Vdc, V <sub>GS</sub> = 0, f = 1.0 MHz)	C <sub>iss</sub>	_	1435	_	pF
Output Capacitance		Coss	_	175		
Reverse Transfer Capacitance		Crss	_	35		
SWITCHING CHARACTERISTICS*					•	
Turn-On Delay Time	$(V_{DD}=300~Vdc,~I_{D}=6.0~Adc,\\ V_{GS}=10~Vdc,\\ R_{g}=9.1~\Omega)$	<sup>t</sup> d(on)	_	22	50	ns
Rise Time		t <sub>r</sub>	_	29	75	
Turn-Off Delay Time		<sup>t</sup> d(off)	_	65	150	
Fall Time		tf	] -	34	65	1
Gate Charge	(V <sub>DS</sub> = 420 Vdc, I <sub>D</sub> = 6.0 Adc, V <sub>GS</sub> = 10 Vdc)	QT	l –	50	60	nÇ
		Q <sub>1</sub>		8.0	_	
		Q <sub>2</sub>	_	26	_	
		Q <sub>3</sub>	_	30	_	
SOURCE-DRAIN DIODE CHARACT	ERISTICS*					
Forward On-Voltage	(I <sub>S</sub> = 6.0 Adc, V <sub>GS</sub> = 0) (I <sub>S</sub> = 6.0 Adc, V <sub>GS</sub> = 0, T <sub>J</sub> = 125°C)	V <sub>SD</sub>	  -  -	1.3 1.2	1.5 —	Vdc
Reverse Recovery Time	(I <sub>S</sub> = 6.0 Adc, V <sub>GS</sub> = 0, dig/dt = 100 A/μs)	t <sub>rr</sub>		330	_	ns
		ta		220	_	
		t <sub>b</sub>	-	110	_	1
Reverse Recovery Stored Charge		Q <sub>RR</sub>	_	4.3	_	μC
NTERNAL PACKAGE INDUCTANO	E					
Internal Drain Inductance (Measured from the drain lead 0	25" from package to center of die)	LD	_	5.0	_	nH
Internal Source Inductance (Measured from the source lead	0.25" from package to source bond pad)	LS		13		nH

<sup>\*</sup>Pulse Test. Pulse Width ≤ 300 µs, Duty Cycle ≤ 2%

<sup>+</sup> Switching characteristics are independent of operating junction temperature